

PTO/SB/08a (08-03)

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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				Application Number	10/625,201
				Filing Date	7/22/2003
				First Named Inventor	Davis et al.
				Art Unit	2621
				Examiner Name	Not Known
Sheet	1	of	2	Attorney Docket Number	C03-002

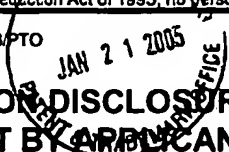
U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code <sup>2</sup> (if known)			
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		Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (if known)					

Examiner Signature		Date Considered	3/1/07
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)		<b>Complete if Known</b>			
		Application Number	10/625,201		
		Filing Date	7/22/2003		
		First Named Inventor	Davis et al.		
		Art Unit	2621		
Examiner Name	Not Known				
Sheet	2	of	2	Attorney Docket Number	C03-002

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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Examiner Signature		Date Considered	3/1/07
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**INFORMATION DISCLOSURE  
 STATEMENT BY APPLICANT**  
 (Use as many sheets as necessary)



Complete if Known

Application Number 10/625,201  
 Filing Date July 22, 2003  
 First Named Inventor Davis, Jason  
 Group Art Unit  
 Examiner Name Unknown

Sheet 1 of 2

Attorney Docket No: C03-002

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Examiner Initials *	Cite No. *	Foreign Document No Country Code - Number - Kind Code (if known)	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>2</sup>
		DE-DE 44 06 020	06/29/1995	Konen, Wolfgang, et al.		
		C1				

**OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS**

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DATE CONSIDERED

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Substitute Disclosure Statement Form (PTO-1449)  
 \* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

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Complete if Known

Application Number	10/625,201
Filing Date	July 22, 2003
First Named Inventor	Davis, Jason
Group Art Unit	0
Examiner Name	Unknown

Sheet 2 of 2

Attorney Docket No: C03-002

**OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T*
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Substitute Disclosure Statement Form (PTO-1449)

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